



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Inventor	Joonhyung Kwon	Filing Date	December 29, 2003
Art Unit	2856	Examiner	LARKIN, Daniel Sean
Title:	Scanning Probe Microscope With Improved Probe Tip Mount		
Docket No.:	PSI004-1C US	Application No.	10/748,827

Santa Clara, California  
February 1, 2005

Mail Stop AMENDMENT  
COMMISSIONER FOR PATENTS  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT**

Dear Sir:

This amendment is in response to the Office Action dated November 1, 2004.

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 3 of this paper.

**Amendments to the Drawings** begin on page 8 of this paper and include both an attached replacement sheet and an annotated sheet showing changes.

**Remarks/Arguments** begin on page 9 of this paper.

An **Appendix** of one sheet which includes amended drawing figures is attached, following page 13 of this paper.